

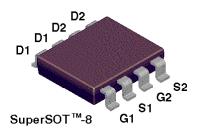
NDH8301N Dual N-Channel Enhancement Mode Field Effect Transistor

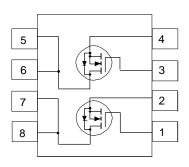
General Description

These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, high cell density, DMOS technology. This very high density process is especially tailored to minimize on-state resistance. These devices are particularly suited for low voltage applications such as notebook computer power management, and other battery powered circuits where fast switching, and low in-line power loss are needed in a very small outline surface mount package.

Features

- Proprietary SuperSOTTM-8 package design using copper lead frame for superior thermal and electrical capabilities.
- High density cell design for extremely low R_{DS(ON)}.
- Exceptional on-resistance and maximum DC current capability.





Absolute Maximum Ratings T_a = 25°C unless otherwise note

Symbol	Parameter		NDH8301N	Units
V _{DSS}	Drain-Source Voltage		20	V
V _{GSS}	Gate-Source Voltage		8	V
I _D	Drain Current - Continuous	(Note 1)	3	A
	- Pulsed		15	
P _D	Maximum Power Dissipation	(Note 1)	0.8	W
T_J , T_{STG}	Operating and Storage Temperature Range	де	-55 to 150	°C
THERMA	L CHARACTERISTICS	•		
R _{OJA}	Thermal Resistance, Junction-to-Ambient	(Note 1)	156	°C/W
R _{ØJC}	Thermal Resistance, Junction-to-Case	(Note 1)	40	°C/W

Symbol	Parameter	Conditions	Min	Тур	Max	Units	
OFF CHA	RACTERISTICS						
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_{D} = 250 \mu\text{A}$		20			V
DSS	Zero Gate Voltage Drain Current	V _{DS} = 16 V, V _{GS} = 0 V				1	μA
			$T_J = 55^{\circ}C$			10	μA
GSSF	Gate - Body Leakage, Forward	$V_{GS} = 8 \text{ V}, V_{DS} = 0 \text{ V}$	·			100	nA
GSSR	Gate - Body Leakage, Reverse	$V_{GS} = -8 \text{ V}, V_{DS} = 0 \text{ V}$				-100	nA
ON CHAR	RACTERISTICS (Note 2)						•
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$		0.4	0.7	1	V
			T _J = 125°C	0.3	0.45	0.8	
R _{DS(ON)}	Static Drain-Source On-Resistance	$V_{GS} = 4.5 \text{ V}, I_{D} = 3 \text{ A}$			0.047	0.06	Ω
			T _J = 125°C		0.07	0.11	
		$V_{GS} = 2.7 \text{ V}, I_{D} = 2.6 \text{ A}$	•		0.059	0.075	
D(on)	On-State Drain Current $V_{GS} = 4.5 \text{ V}, V_{DS} = 5 \text{ V}$						Α
		$V_{GS} = 2.7 \text{ V}, V_{DS} = 5 \text{ V}$	5				
) _{FS}	Forward Transconductance	$V_{DS} = 5 \text{ V}, I_{D} = 3 \text{ A}$		10		S	
OYNAMIC	CHARACTERISTICS	·					
Ciss	Input Capacitance	DS 7 GS 7			415		pF
O _{oss}	Output Capacitance	f = 1.0 MHz			220		pF
C _{rss}	Reverse Transfer Capacitance				85		pF
SWITCHIN	G CHARACTERISTICS (Note 2)						
D(on)	Turn - On Delay Time	$V_{DD} = 5 \text{ V}, I_{D} = 1 \text{ A},$			8	15	ns
r	Turn - On Rise Time	V_{GS} = 4.5 V, R_{GEN} = 6 Ω			25	45	ns
D(off)	Turn - Off Delay Time			30	55	ns	
f	Turn - Off Fall Time				8	15	ns
Q_{g}	Total Gate Charge	$V_{DS} = 10 \text{ V},$			10	15	nC
Q_{gs}	Gate-Source Charge	$I_D = 3 \text{ A}, \ V_{GS} = 4.5 \text{ V}$			0.9		nC
Q_{gd}	Gate-Drain Charge				3.5		nC

ELECTRICAL CHARACTERISTICS (T _A = 25°C unless otherwise noted)									
Symbol	Parameter Conditions Min Typ Max Units								
DRAIN-SOURCE DIODE CHARACTERISTICS AND MAXIMUM RATINGS									
I _s	Maximum Continuous Drain-Source Diode Forward Current 0.67								
V _{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = 0.67 \text{ A} \text{ (Note 2)}$		0.7	1.2	V			

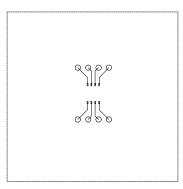
Notes:

1. R_{BAR} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R_{BAC} is guaranteed by design while R_{BAC} is determined by the user's board design.

$$P_{D}(t) = \frac{T_{J} T_{A}}{R_{\theta J} \oint t} = \frac{T_{J} T_{A}}{R_{\theta J} \oint R_{\theta C} \oint t} = I_{D}^{2}(t) \times R_{DS(ON)} \mathcal{P}_{TJ}$$

Typical $R_{_{BUA}}$ for single device operation using the board layouts shown below on 4.5"x5" FR-4 PCB in a still air environment:

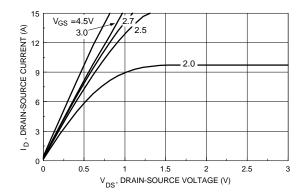
156°C/W when mounted on a 0.0025 in² pad of 2oz copper.



Scale 1 : 1 on letter size paper.

2. Pulse Test: Pulse Width $\leq 300 \mu s,$ Duty Cycle $\leq 2.0\%.$

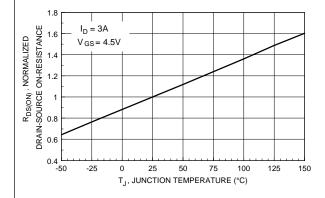
Typical Electrical Characteristics



2 QBZ 1.75 VGS= 2.0V VGS= 2.0V VGS= 2.0V VGS= 2.0V 1.5 QBZ 2.7 QBZ

Figure 1. On-Region Characteristics.

Figure 2. On-Resistance Variation with Gate Voltage and Drain Current.



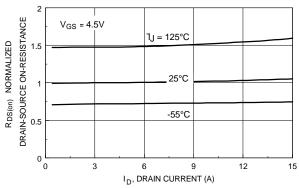
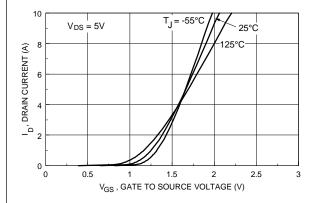


Figure 3. On-Resistance Variation with Temperature.

Figure 4. On-Resistance Variation with Drain Current and Temperature.



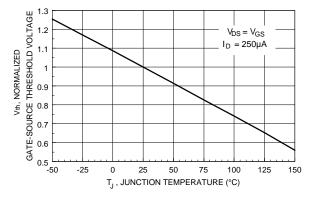


Figure 5. Transfer Characteristics.

Figure 6. Gate Threshold Variation with Temperature.

Typical Electrical Characteristics

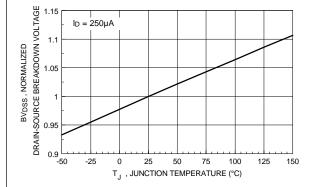


Figure 7. Breakdown Voltage Variation with Temperature.

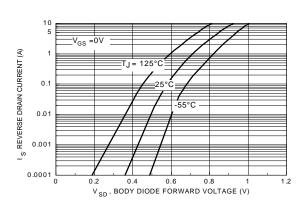


Figure 8. Body Diode Forward Voltage Variation with Current and Temperature.

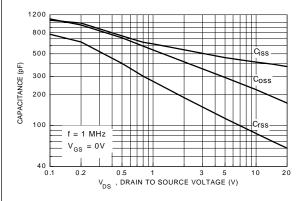


Figure 9. Capacitance Characteristics.

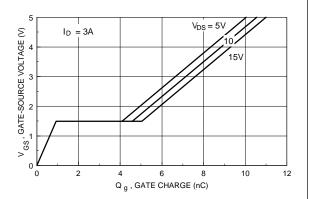


Figure 10. Gate Charge Characteristics.

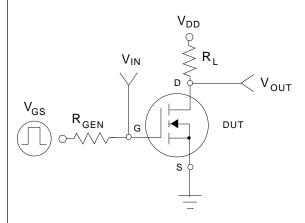


Figure 11. Switching Test Circuit.

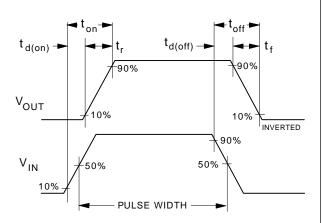
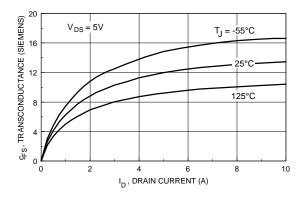


Figure 12. Switching Waveforms.

Typical Electrical and Thermal Characteristics



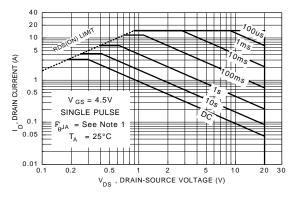


Figure 13. Transconductance Variation with Drain Current and Temperature.

Figure 14. Maximum Safe Operating Area.

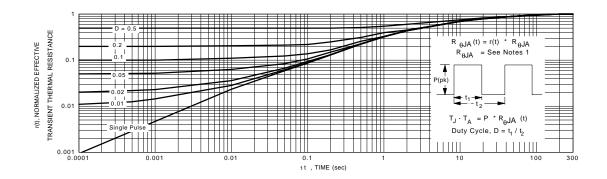
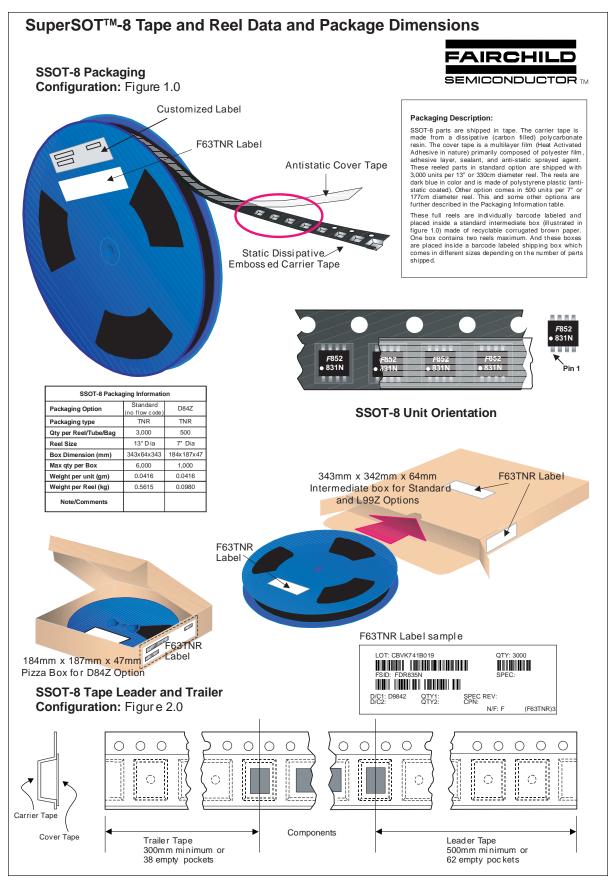


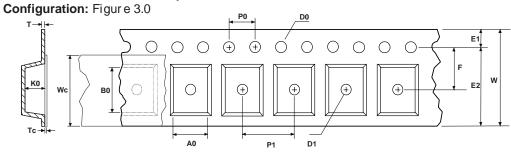
Figure 15. Transient Thermal Response Curve.

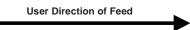
Note: Thermal characterization performed using the conditions described in note 1. Transient thermal response will change depending on the circuit board design.





SSOT-8 Embossed Carrier Tape



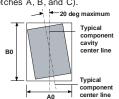


	Dimensions are in millimeter													
Pkg type	A0	В0	w	D0	D1	E1	E2	F	P1	P0	K0	Т	Wc	Тс
SSOT-8 (12mm)	4.47 +/-0.10	5.00 +/-0.10	12.0 +/-0.3	1.55 +/-0.05	1.50 +/-0.10	1.75 +/-0.10	10.25 min	5.50 +/-0.05	8.0 +/-0.1	4.0 +/-0.1	1.37 +/-0.10	0.280 +/-0.150	9.5 +/-0.025	0.06 +/-0.02

Notes: A0, B0, and K0 dimensions are determined with respect to the EIA/Jedec RS-481 rotational and lateral movement requirements (see sketches A, B, and C).



Sketch A (Side or Front Sectional View)
Component Rotation

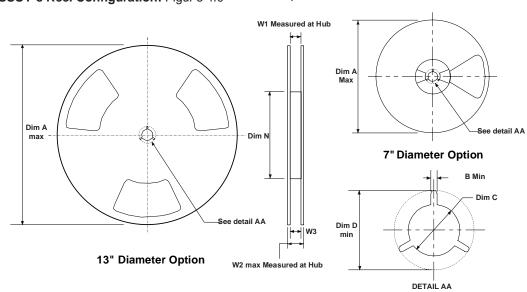


Sketch B (Top View)
Component Rotation



Sketch C (Top View)
Component lateral movement

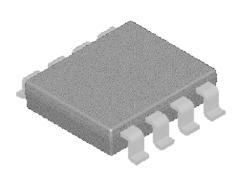
SSOT-8 Reel Configuration: Figur e 4.0

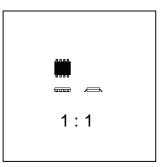


	Dimensions are in inches and millimeters								
Tape Size	Reel Option	Dim A	Dim B	Dim C	Dim D	Dim N	Dim W1	Dim W2	Dim W3 (LSL-USL)
12mm	7" Dia	7.00 177.8	0.059 1.5	512 +0.020/-0.008 13 +0.5/-0.2	0.795 20.2	5.906 150	0.488 +0.078/-0.000 12.4 +2/0	0.724 18.4	0.469 - 0.606 11.9 - 15.4
12mm	13" Dia	13.00 330	0.059 1.5	512 +0.020/-0.008 13 +0.5/-0.2	0.795 20.2	7.00 178	0.488 +0.078/-0.000 12.4 +2/0	0.724 18.4	0.469 - 0.606 11.9 - 15.4

SuperSOT™-8 Tape and Reel Data and Package Dimensions, continued

SuperSOT™-8 (FS PKG Code 34, 35)

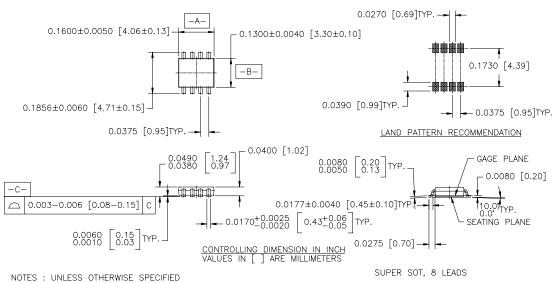




Scale 1:1 on letter size paper

Dimensions shown below are in: inches [millimeters]

Part Weight per unit (gram): 0.0416



STANDARD LEAD FINISH TI BE 200 MICROINCHES / 5.08 MICROMETERS MINIMUM TIN/LEAD (SOLDER) ON COPPER.

2. NO JEDEC REGISTRATION AS JAN. 1996

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